

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/659,055	AERTGEERTS ET AL.
	<b>Examiner</b> Nashaat T. Nashed, Ph. D.	<b>Art Unit</b> 1656

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
SEQ ID NO: 3 and 1 (residues 39-766) search in pending files		8/23/2007	NASH